

**Search Notes****Application/Control No.**

10/764,481

**Examiner**

MARK A. MAIS

**Applicant(s)/Patent under Reexamination**

HIYAMA ET AL.

**Art Unit**

2419

**SEARCHED**

Class	Subclass	Date	Examiner
370	310 328	11/20/2008	MAM
	329 331		
	338 351		
	352 353		
	389 392		
	401 469		
	474 475 476		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
<b>Search</b>	<b>Performed</b>	11/20/2008	<b>MAM</b>

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
See Inventorship Search	6/16/2007	MAM
See Attached Electronic Search	6/16/2007	MAM
See Attached Electronic Search [updated]	3/30/2008	MAM
See Attached Electronic Search [updated]	8/18/2008	MAM
See Attached Electronic Search [updated]	11/20/2008	MAM
See Interference Search	11/20/2008	MAM